Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/038,271	FALLAUX ET AL.
Examiner	Art Unit

Dave T. Nguyen

1632

SEARCHED					
Class	Subclass	Date	Examiner		
same as	set forht previously	5/30/2005	DTN		
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INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Inventor names searched, related applications checked	5/31/2005	DTN
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